

General Description:

60N20 the silicon N-channel Enhanced VDMOSFETs, is obtained by the self-aligned planar Technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor can be used in various power switching circuit for system miniaturization and higher efficiency. The package form is TO-220AB, which accords with the RoHS standard.

Features:

- | **Fast Switching**
- | **Low ON Resistance($R_{DS(on)} \leq 46m\Omega$)**
- | **Low Gate Charge (Typical Data: 56.9nC)**
- | **Low Reverse transfer capacitances(Typical:46pF)**
- | **100% Single Pulse avalanche energy Test**

Applications:

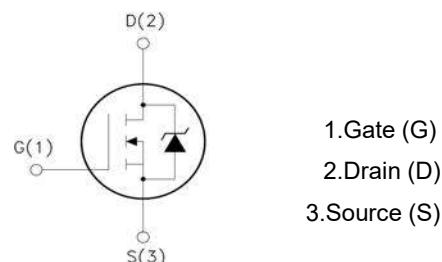
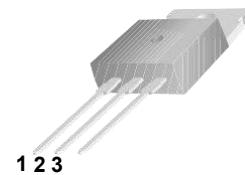
Power switch circuit of adaptor and charger.

Absolute ($T_c = 25^\circ C$ unless otherwise specified):

Symbol	Parameter	Rating	Units
V_{DSS}	Drain-to-Source Voltage	200	V
I_D	Continuous Drain Current	60	A
	Continuous Drain Current $T_c = 100^\circ C$	40.8	A
I_{DM}^{a1}	Pulsed Drain Current	240	A
V_{GS}	Gate-to-Source Voltage	± 30	V
E_{AS}^{a2}	Single Pulse Avalanche Energy	2000	mJ
dv/dt^{a3}	Peak Diode Recovery dv/dt	5.0	V/ns
P_D	Power Dissipation	300	W
	Derating Factor above $25^\circ C$	2.4	W/ $^\circ C$
T_J, T_{stg}	Operating Junction and Storage Temperature Range	150, -55 to 150	$^\circ C$
T_L	Maximum Temperature for Soldering	300	$^\circ C$

V_{DSS}	200	V
I_D	60	A
$P_D(T_c=25^\circ C)$	300	W
$R_{DS(ON)Typ}$	39	$m\Omega$

TO-220AB



Electrical Characteristics (T_c= 25°C unless otherwise specified):

OFF Characteristics						
Symbol	Parameter	Test Conditions	Rating			Unit
			Min.	Typ.	Max.	
V _{DSS}	Drain to Source Breakdown Voltage	V _{GS} =0V, I _D =250μA	200	--	--	V
Δ BV _{DSS} / Δ T _J	Bvdss Temperature Coefficient	I _D =250uA, Reference 25°C	--	0.3	--	V/°C
I _{DSS}	Drain to Source Leakage Current	V _{DS} =200V, V _{GS} = 0V, T _a = 25°C	--	--	1	μA
		V _{DS} =160V, V _{GS} = 0V, T _a = 125°C	--	--	100	μA
I _{GSS(F)}	Gate to Source Forward Leakage	V _{GS} =+30V	--	--	100	nA
I _{GSS(R)}	Gate to Source Reverse Leakage	V _{GS} =-30V	--	--	-100	nA

ON Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
R _{DS(ON)}	Drain-to-Source On-Resistance	V _{GS} =10V, I _D =30A	--	39	46	mΩ
V _{GS(TH)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = 250μA	2.0	--	4.0	V
Pulse width t _p ≤300μs, δ ≤2%						

Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
g _{fs}	Forward Transconductance	V _{DS} =15V, I _D =30A	--	28	--	S
C _{iss}	Input Capacitance		--	3308	--	
C _{oss}	Output Capacitance	V _{GS} = 0V V _{DS} = 25V f = 1.0MHz	--	520	--	pF
C _{rss}	Reverse Transfer Capacitance		--	46	--	

Resistive Switching Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
t _{d(ON)}	Turn-on Delay Time	I _D =60A V _{DD} = 100V R _G =10Ω	--	36.4	--	ns
tr	Rise Time		--	118	--	
t _{d(OFF)}	Turn-Off Delay Time		--	74.4	--	
t _f	Fall Time		--	56.4	--	
Q _g	Total Gate Charge	I _D =60A V _{DD} =160V V _{GS} = 10V	--	56.9	--	nC
Q _{gs}	Gate to Source Charge		--	18.6	--	
Q _{gd}	Gate to Drain ("Miller")Charge		--	25.8	--	

Source-Drain Diode Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
I _S	Continuous Source Current (Body Diode)		--	--	60	A
I _{SM}	Maximum Pulsed Current (Body Diode)		--	--	240	A
V _{SD}	Diode Forward Voltage	I _S =60A, V _{GS} =0V	--	--	1.5	V
t _{rr}	Reverse Recovery Time	I _S =60A, T _j = 25 °C dI _F /dt=100A/us, V _{GS} =0V	--	--	166	ns
Q _{rr}	Reverse Recovery Charge		--	--	1306	nC
I _{RRM}	Reverse Recovery Current		--	--	14.9	A
Pulse width tp≤300μs, δ ≤2%						

Symbol	Parameter	Max.	Units
R _{θJC}	Junction-to-Case	0.42	°C/W
R _{θJA}	Junction-to-Ambient	62	°C/W

^{a1}: Repetitive rating; pulse width limited by maximum junction temperature

^{a2}: L=10mH, I_D=20A, Start T_j=25 °C

^{a3}: I_{SD} =60A,di/dt ≤100A/us,V_{DD}≤BV_{DS}, Start T_j=25 °C

Characteristics Curve:

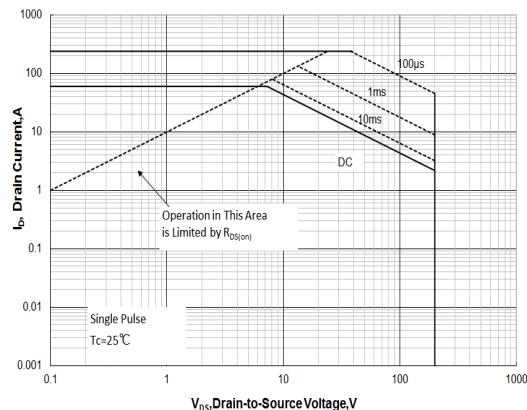


Figure 1 Maximum Forward Bias Safe Operating Area

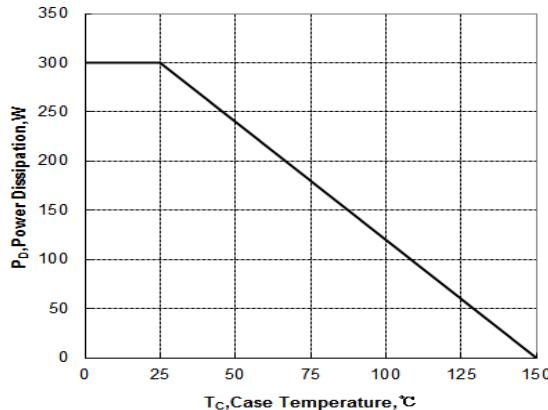


Figure 2 Maximum Power dissipation vs Case Temperature

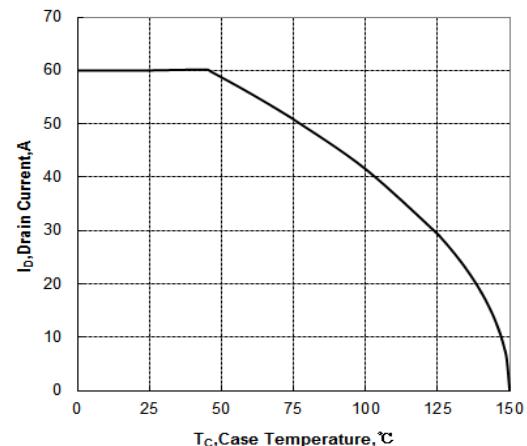


Figure 3 Maximum Continuous Drain Current vs Case Temperature

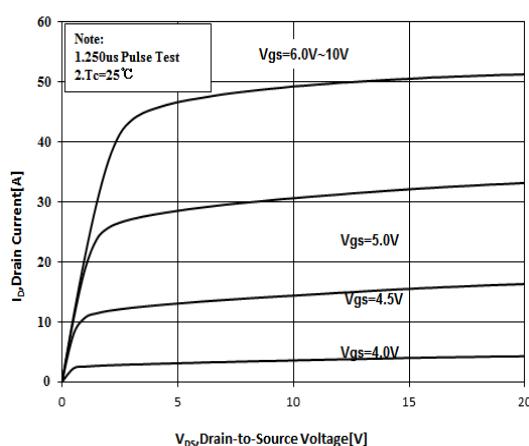


Figure 4 Typical Output Characteristics

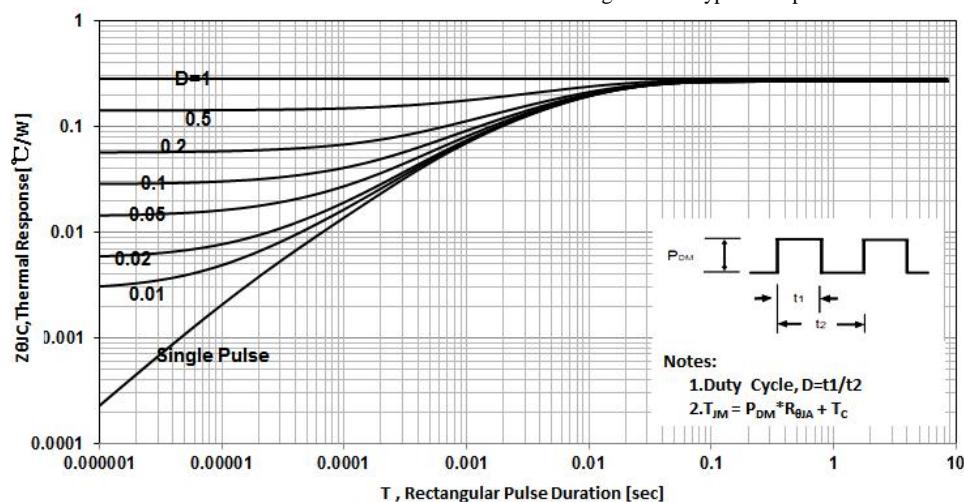


Figure 5 Maximum Effective Thermal Impedance , Junction to Case

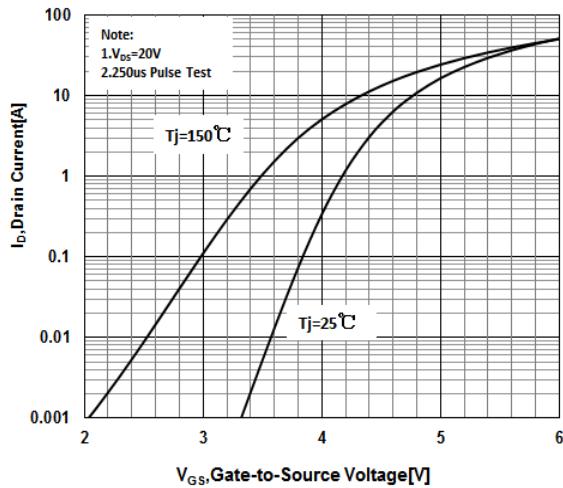


Figure 6 Typical Transfer Characteristics

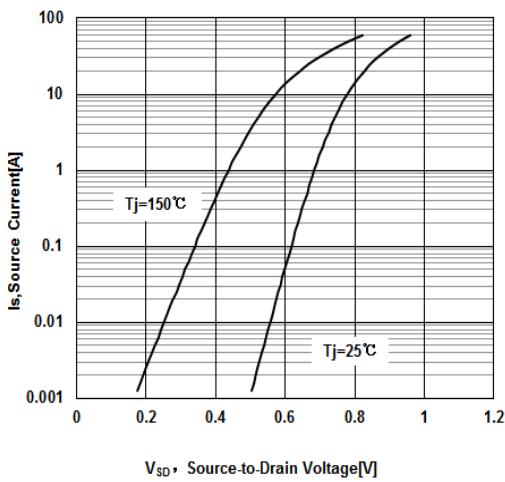


Figure 7 Typical Body Diode Transfer Characteristics

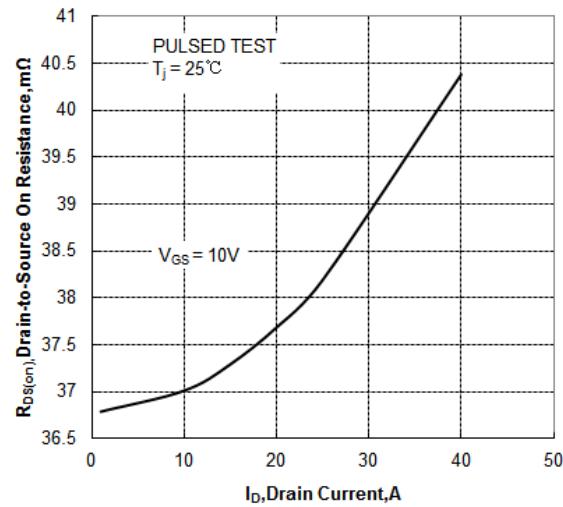


Figure 8 Typical Drain to Source ON Resistance vs Drain Current

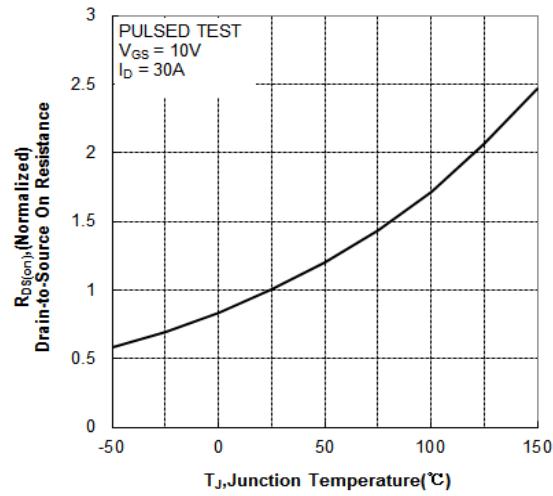


Figure 9 Typical Drian to Source on Resistance vs Junction Temperature

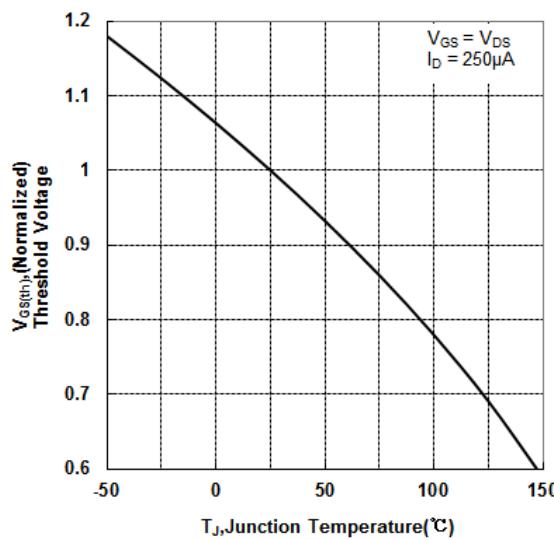


Figure 10 Typical Threshold Voltage vs Junction Temperature

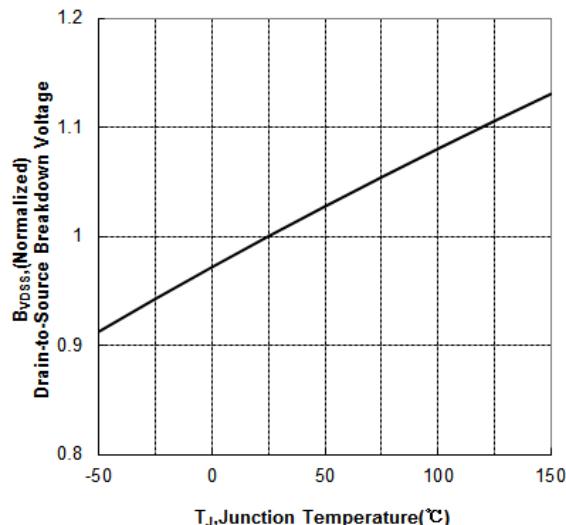


Figure 11 Typical Breakdown Voltage vs Junction Temperature

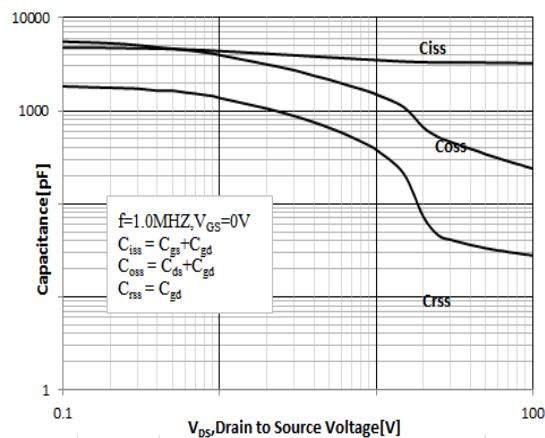


Figure 12 Typical Capacitance vs Drain to Source Voltage

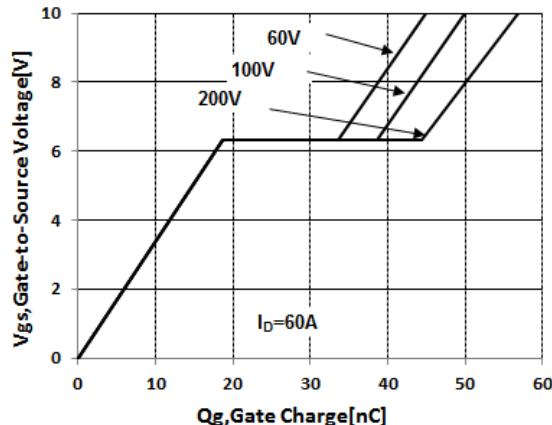


Figure 13 Typical Gate Charge vs Gate to Source Voltage

Test Circuit and Waveform

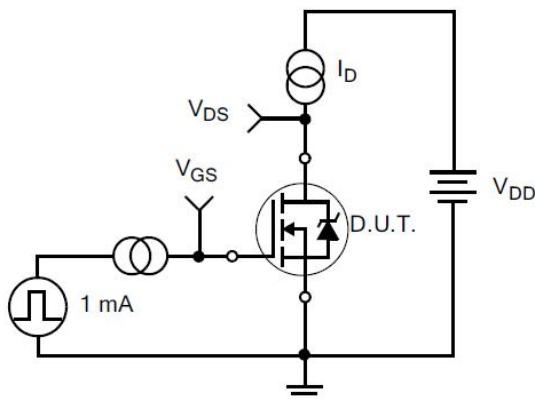


Figure 17. Gate Charge Test Circuit

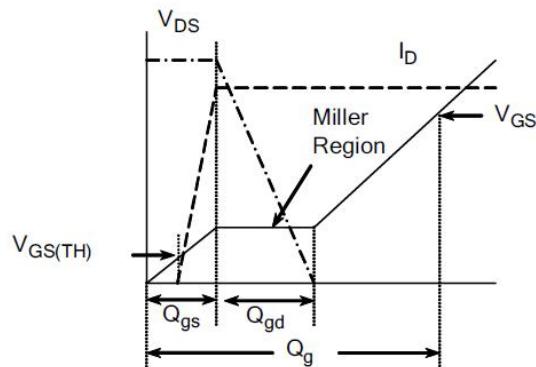


Figure 18. Gate Charge Waveform

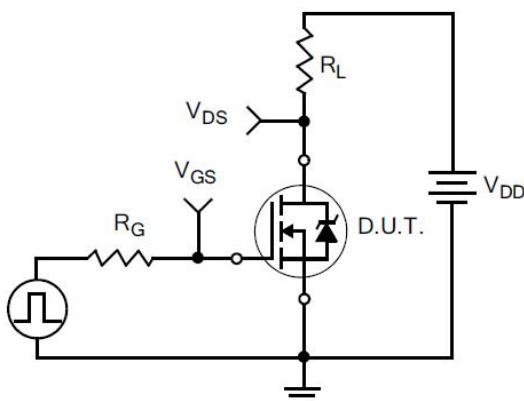


Figure 19. Resistive Switching Test Circuit

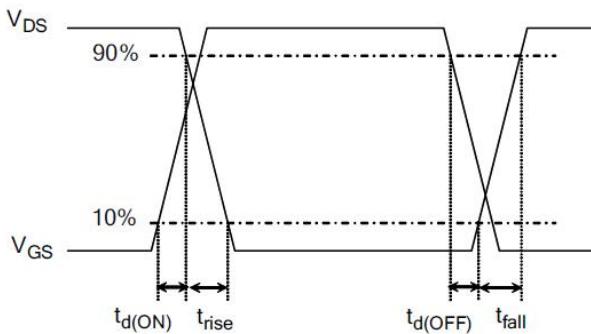


Figure 20. Resistive Switching Waveforms

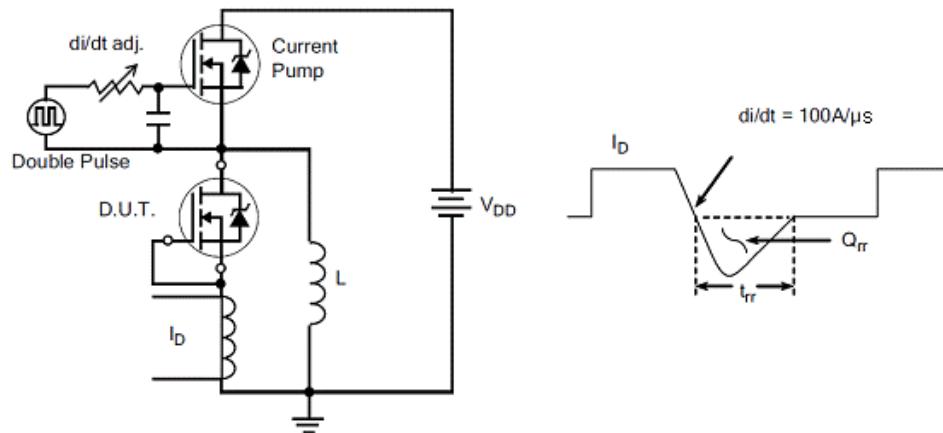


Figure 21. Diode Reverse Recovery Test Circuit

Figure 22. Diode Reverse Recovery Waveform

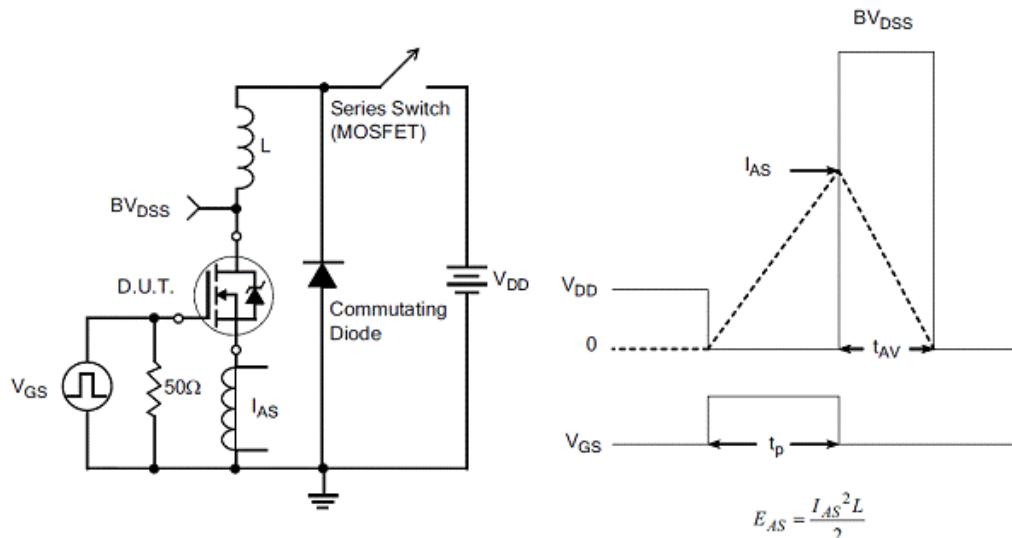
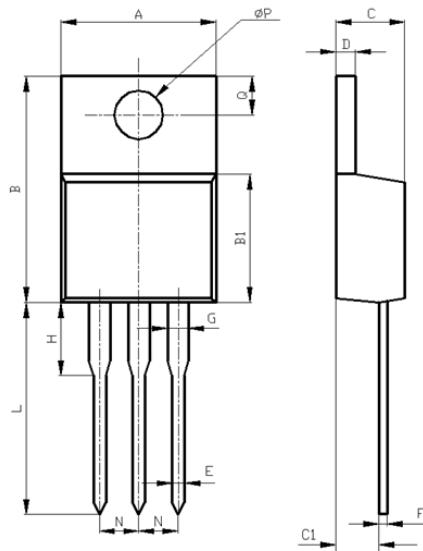


Figure 23. Unclamped Inductive Switching Test Circuit

Figure 24. Unclamped Inductive Switching Waveforms

Package Information



Items	Values(mm)	
	MIN	MAX
A	9.60	10.6
B	15.0	16.0
B1	8.90	9.50
C	4.30	4.80
C1	2.30	3.10
D	1.20	1.40
E	0.70	0.90
F	0.30	0.60
G	1.17	1.37
H	2.70	3.80
L*	12.6	14.8
N	2.34	2.74
Q	2.40	3.00
Φ P	3.50	3.90

*adjustable

TO-220AB Package